DATA SHEET



MOS FIELD EFFECT TRANSISTOR Phase-out/Discontinued μ **ΡΑ1710Α**

SWITCHING P-CHANNEL POWER MOS FET **INDUSTRIAL USE**

DESCRIPTION

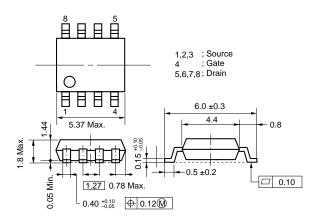
This product is P-Channel MOS Field Effect Transistor designed for DC/DC converter and power management applications of notebook computers.

FEATURES

- · Low on-resistance
- $R_{DS(on)1} = 70 \text{ m}\Omega \text{ (MAX.)} (V_{GS} = -10 \text{ V}, \text{ ID} = -2.5 \text{ A})$ $R_{DS(on)2} = 160 \text{ m}\Omega \text{ (MAX.)} (V_{GS} = -4 \text{ V}, \text{ ID} = -2.0 \text{ A})$
- Low Ciss : Ciss = 840 pF (TYP.)
- · Built-in G-S protection diode
- Small and surface mount package (Power SOP8)

ORDERING INFORMATION

PART NUMBER	PACKAGE
μ PA1710AG	Power SOP8



PACKAGE DRAWING (Unit : mm)

ABSOLUTE MAXIMUM RATINGS (T_A = 25°C, All terminals are connected.)

ABSOLUTE MAXIMUM RATINGS (TA	= 25°C, All	l terminals are co	onnected.)	EQUIVARENT CIRCUIT
Drain to Source Voltage (Vgs = 0 V)	Vdss	-30	V	
Gate to Source Voltage (Vps = 0 V)	Vgss	±20	V	Drain
Drain Current (DC)	ID(DC)	±5.0	А	. 🗖
Drain Current (pulse) Note1	D(pulse)	±20	А	Gate ⊢ Body
Total Power Dissipation $(T_A = 25^{\circ}C)^{Note2}$	P⊤	2.0	W	
Channel Temperature	Tch	150	°C	Gate
Storage Temperature	Tstg	–55 to + 150	°C	Protection Source Diode

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1 %

- 2. Mounted on ceramic substrate of 1200 mm² x 1.1 mm
- **Remark** The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

The information in this document is subject to change without notice.

Document No. G11497EJ1V1DS00 (1st edition) Date Published November 1998 NS CP(K) Printed in Japan

© NEC Corporation 1995

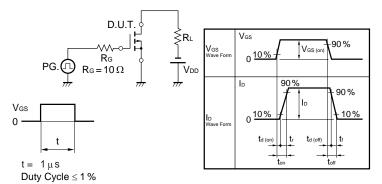
NEC



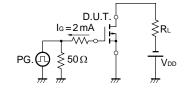
ELECTRICAL CHARACTERISTICS (TA = 25 °C, All terminals are connected.)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	Vgs = −10 V, Id = −2.5 A		45	70	mΩ
	RDS(on)2	$V_{GS} = -4 V$, $I_D = -2.0 A$		91	160	mΩ
Gate to Source Cut-off Voltage	VGS(off)	$V_{DS} = -10 V$, $I_{D} = -1 mA$	-1.0	-1.8	-2.5	V
Forward Transfer Admittance	yfs	Vds = -10 V, Id = -2.5 A	3.0	5.6		S
Drain Leakage Current	loss	$V_{DS} = -30 V$, $V_{GS} = 0 V$			-10	μA
Gate to Source Leakage Current	lgss	$V_{GS} = \pm 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			±10	μA
Input Capacitance	Ciss	Vbs = -10 V		840		pF
Output Capacitance	Coss	V _{GS} = 0 V		570		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		190		pF
Turn-on Delay Time	td(on)	I⊳ = −2.5 A		13		ns
Rise Time	tr	$V_{GS(on)} = -10 V$		66		ns
Turn-off Delay Time	td(off)	VDD = -15 V		82		ns
Fall Time	tr	$R_G = 10 \Omega$		52		ns
Total Gate Charge	QG	I⊳ = −5.0 A		27.3		nC
Gate to Source Charge	QGS	$V_{DD} = -24 V$		2.7		nC
Gate to Drain Charge	Qgd	$V_{GS} = -10 V$		8.2		nC
Body Diode Forward Voltage	VF(S-D)	IF = 5.0 A, VGS = 0 V		0.81		V
Reverse Recovery Time	trr	IF = 5.0 A, VGS = 0 V		61		ns
Reverse Recovery Charge	Qrr	di/dt = 50 A/ μ s		71		nC

TEST CIRCUIT 1 SWITCHING TIME



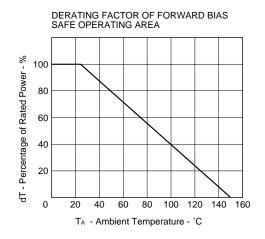
TEST CIRCUIT 2 GATE CHARGE



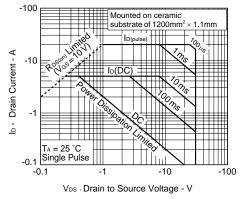
NEC

Phase-out/Discontinued

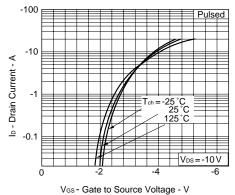
TYPICAL CHARACTERISTICS (TA = 25 °C)

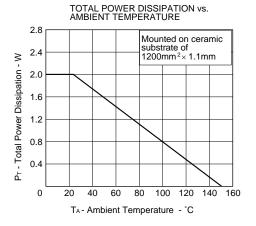




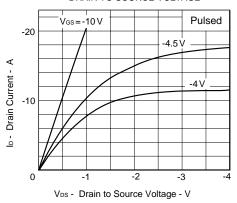


FORWARD TRANSFER CHARACTERISTICS





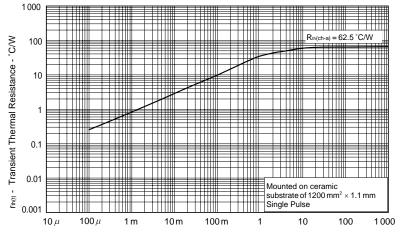




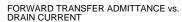
NEC

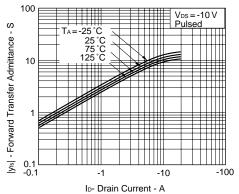
Phase-out/Discontinued

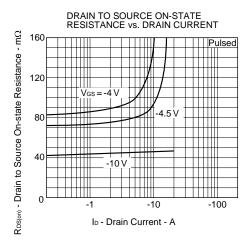
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



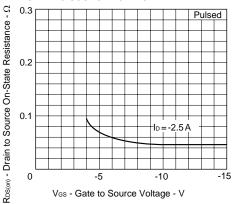




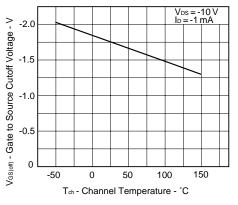




DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



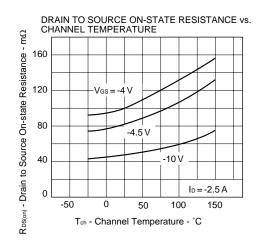
GATE TO SOURCE CUTOFF VOLTAGE vs. CHANNEL TEMPERATURE

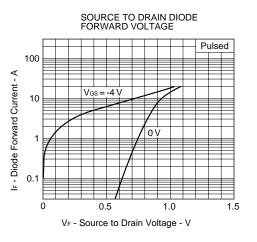


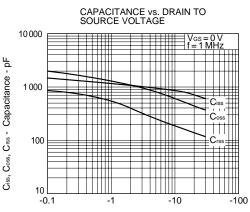
μ PA1710A

NEC

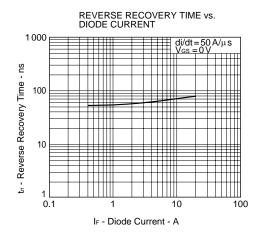
Phase-out/Discontinued



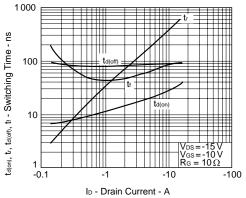


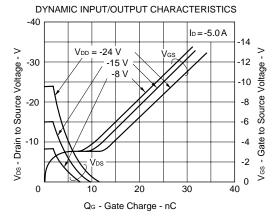






SWITCHING CHARACTERISTICS





NEC

Phase-out/Discontinued

[MEMO]

NEC

Phase-out/Discontinued

[MEMO]

Phase-out/Discontinued

No part of this document may be copied or reproduced in any form or by any means without the prior written consent of NEC Corporation. NEC Corporation assumes no responsibility for any errors which may appear in this document.

NEC Corporation does not assume any liability for infringement of patents, copyrights or other intellectual property rights of third parties by or arising from use of a device described herein or any other liability arising from use of such device. No license, either express, implied or otherwise, is granted under any patents, copyrights or other intellectual property rights of NEC Corporation or others.

While NEC Corporation has been making continuous effort to enhance the reliability of its semiconductor devices, the possibility of defects cannot be eliminated entirely. To minimize risks of damage or injury to persons or property arising from a defect in an NEC semiconductor device, customers must incorporate sufficient safety measures in its design, such as redundancy, fire-containment, and anti-failure features.

NEC devices are classified into the following three quality grades:

"Standard", "Special", and "Specific". The Specific quality grade applies only to devices developed based on a customer designated "quality assurance program" for a specific application. The recommended applications of a device depend on its quality grade, as indicated below. Customers must check the quality grade of each device before using it in a particular application.

- Standard: Computers, office equipment, communications equipment, test and measurement equipment, audio and visual equipment, home electronic appliances, machine tools, personal electronic equipment and industrial robots
- Special: Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support)
- Specific: Aircrafts, aerospace equipment, submersible repeaters, nuclear reactor control systems, life support systems or medical equipment for life support, etc.

The quality grade of NEC devices is "Standard" unless otherwise specified in NEC's Data Sheets or Data Books. If customers intend to use NEC devices for applications other than those specified for Standard quality grade, they should contact an NEC sales representative in advance.

Anti-radioactive design is not implemented in this product.

M4 96.5